

March 2013

FDD5N60NZ

N-Channel UniFETTM II MOSFET 600 V, 4.0 A, 2 Ω

Features

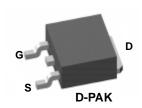
- $R_{DS(on)} = 1.65 \Omega (Typ.) @ V_{GS} = 10 V, I_D = 2.0 A$
- Low Gate Charge (Typ. 10 nC)
- Low C_{rss} (Typ. 5 pF)
- 100% Avalanche Tested
- · Improved dv/dt Capability
- · ESD Improved Capability
- RoHS Compliant

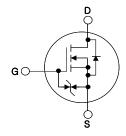
Applications

- LCD/LED/PDP TV
- · Lighting
- Uninterruptible Power Supply

Description

UniFETTM II MOSFET is Fairchild Semiconductor[®] s high voltage MOSFET family based on advanced planar stripe and DMOS technology. This advanced MOSFET family has the smallest on-state resistance among the planar MOSFET, and also provides superior switching performance and higher avalanche energy strength. In addition, internal gate-source ESD diode allows UniFET II MOSFET to withstand over 2kV HBM surge stress. This device family is suitable for switching power converter applications such as power factor correction (PFC), flat panel display (FPD) TV power, ATX and electronic lamp ballasts.





MOSFET Maximum Ratings T_C = 25°C unless otherwise noted*

Symbol		Parameter		FDD5N60NZ	Unit	
V _{DSS}	Drain to Source Voltage			600	V	
V _{GSS}	Gate to Source Voltage			±25	V	
1	Drain Current	- Continuous (T _C = 25°C)		4.0	^	
ID	Drain Current	- Continuous (T _C = 100°C)		2.4	A	
I _{DM}	Drain Current	- Pulsed	(Note 1)	16	Α	
E _{AS}	Single Pulsed Avalanche Energ	gy	(Note 2)	216	mJ	
I _{AR}	Avalanche Current		(Note 1)	4.0	Α	
E _{AR}	Repetitive Avalanche Energy		(Note 1)	8.3	mJ	
dv/dt	Peak Diode Recovery dv/dt		(Note 3)	10	V/ns	
D	Davis Dissination	$(T_C = 25^{\circ}C)$		83	W	
P_{D}	Power Dissipation	- Derate above 25°C		0.7	W/°C	
T _J , T _{STG}	Operating and Storage Temper	rature Range		-55 to +150	°C	
TL	Maximum Lead Temperature for 1/8" from Case for 5 Seconds	or Soldering Purpose,		300	°C	

Thermal Characteristics

Symbol	Parameter	FDD5N60NZ	Unit
$R_{\theta JC}$	Thermal Resistance, Junction to Case, Max. 1.5		°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient, Max.	90	

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDD5N60NZ	FDD5N60NZ	D-PAK	380mm	16mm	2500

Electrical Characteristics $T_C = 25^{\circ}C$ unless otherwise noted

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
Off Charac	cteristics					
BV _{DSS}	Drain to Source Breakdown Voltage	$I_D = 250\mu A, V_{GS} = 0V, T_J = 25^{\circ}C$	600	-	-	V
$\frac{\Delta BV_{DSS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	I _D = 250μA, Referenced to 25°C	-	0.6	-	V/°C
	Zero Gate Voltage Drain Current	$V_{DS} = 600V, V_{GS} = 0V$	-	-	50	μА
IDSS	Zero Gate Voltage Drain Current	$V_{DS} = 480V, T_{C} = 125^{\circ}C$	-	-	100	μΑ
I _{GSS}	Gate to Body Leakage Current	$V_{GS} = \pm 25V, V_{DS} = 0V$	-	-	±10	μΑ

On Characteristics

V _{GS(th)}	Gate Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = 250 \mu A$	3.0	-	5.0	V
R _{DS(on)}	Static Drain to Source On Resistance	$V_{GS} = 10V, I_D = 2.0A$	•	1.65	2.00	Ω
g _{FS}	Forward Transconductance	$V_{DS} = 20V, I_{D} = 2.0A$	ı	5	-	S

Dynamic Characteristics

C _{iss}	Input Capacitance	V 05V V 0V	-	450	600	pF
C _{oss}	Output Capacitance	$V_{DS} = 25V, V_{GS} = 0V$ f = 1MHz		50	65	pF
C _{rss}	Reverse Transfer Capacitance	1 - 11/11/2	-	5	7.5	pF
Q _{g(tot)}	Total Gate Charge at 10V		-	10	13	nC
Q_{gs}	Gate to Source Gate Charge	$V_{DS} = 400V, I_{D} = 4.0A$	-	2.5	-	nC
Q_{gd}	Gate to Drain "Miller" Charge	V _{GS} = 10V (Note	4) -	4	-	nC

Switching Characteristics

	•						
t _{d(on)}	Turn-On Delay Time			-	15	40	ns
t _r	Turn-On Rise Time	$V_{DD} = 250V, I_{D} = 4.0A$		-	20	50	ns
t _{d(off)}	Turn-Off Delay Time	$V_{GS} = 10V, R_G = 25\Omega$		-	35	80	ns
t _f	Turn-Off Fall Time		(Note 4)	-	20	50	ns

Drain-Source Diode Characteristics

I _S	Maximum Continuous Drain to Source Diode Forward Current		-	-	4.0	Α
I _{SM}	Maximum Pulsed Drain to Source Diode Forward Current		-	-	16	Α
V_{SD}	Drain to Source Diode Forward Voltage	$V_{GS} = 0V, I_{SD} = 4.0A$	-	-	1.4	V
t _{rr}	Reverse Recovery Time	V _{GS} = 0V, I _{SD} = 4.0A	-	230	-	ns
Q _{rr}	Reverse Recovery Charge	$dI_F/dt = 100A/\mu s$	-	0.9	-	μС

Notes

- ${\bf 1.}\ {\bf Repetitive}\ {\bf Rating:}\ {\bf Pulse}\ {\bf width}\ {\bf limited}\ {\bf by}\ {\bf maximum}\ {\bf junction}\ {\bf temperature}$
- 2. L = 27mH, I $_{AS}$ = 4.0A, V $_{DD}$ = 50V, R $_{G}$ = 25 $\!\Omega$, Starting T $_{J}$ = 25°C
- 3. I $_{SD} \leq$ 4.0A, di/dt \leq 200A/ μ s, $V_{DD} \leq$ BV $_{DSS}$, Starting T $_{J}$ = 25°C
- 4. Essentially Independent of Operating Temperature Typical Characteristics

Typical Performance Characteristics

Figure 1. On-Region Characteristics

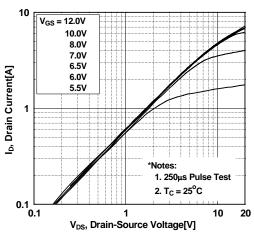


Figure 3. On-Resistance Variation vs.

Drain Current and Gate Voltage

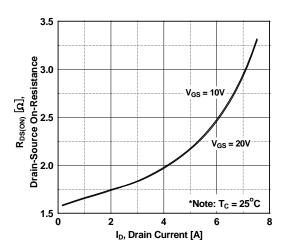


Figure 5. Capacitance Characteristics

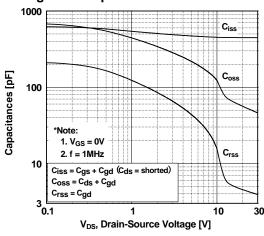


Figure 2. Transfer Characteristics

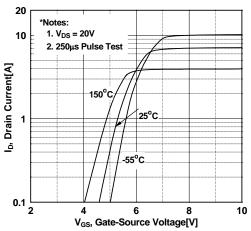


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

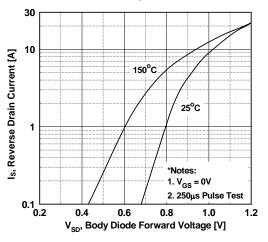
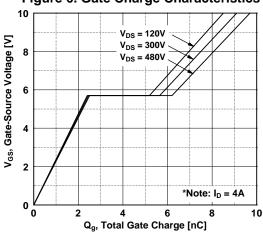


Figure 6. Gate Charge Characteristics



Typical Performance Characteristics (Continued)

Figure 7. Breakdown Voltage Variation vs. Temperature

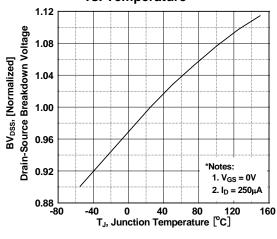


Figure 8. On-Resistance Variation vs. Temperature

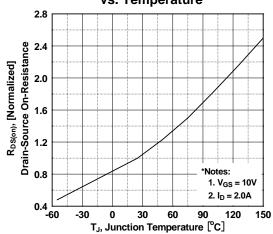


Figure 9. Maximum Safe Operating Area vs. Case Temperature

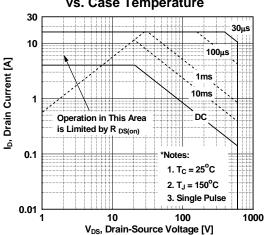


Figure 10. Maximum Drain Current

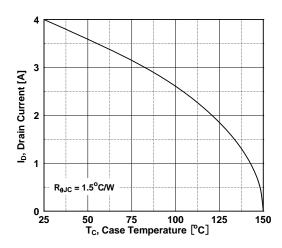
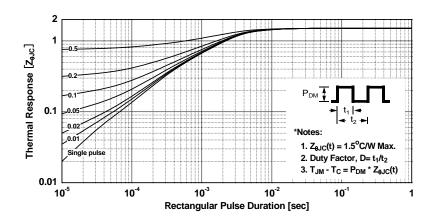
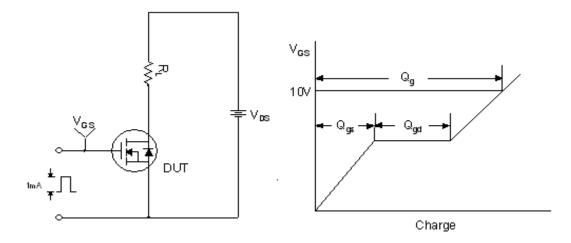


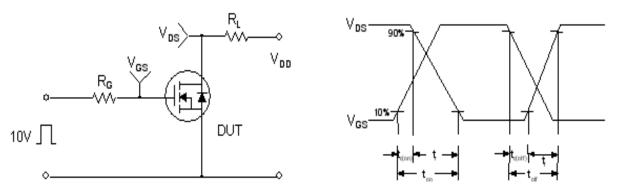
Figure 11. Transient Thermal Response Curve



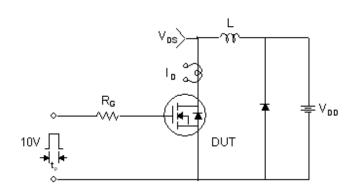
Gate Charge Test Circuit & Waveform

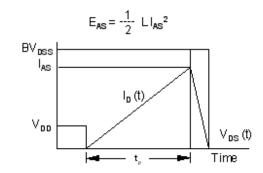


Resistive Switching Test Circuit & Waveforms

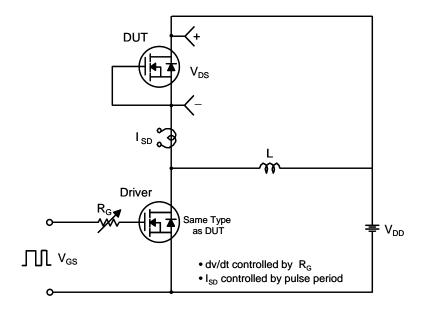


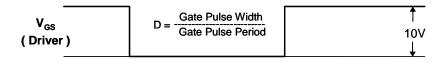
Unclamped Inductive Switching Test Circuit & Waveforms

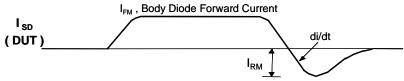




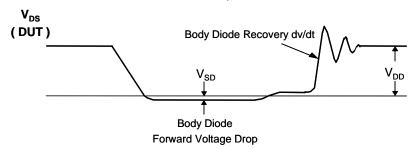
Peak Diode Recovery dv/dt Test Circuit & Waveforms





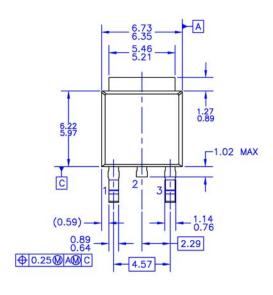


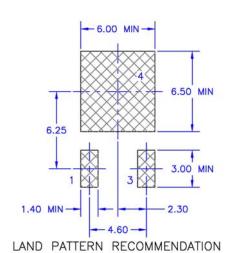
Body Diode Reverse Current

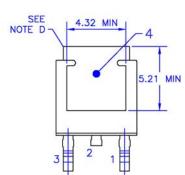


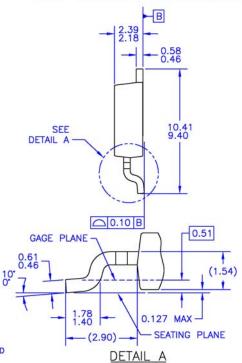
Mechanical Dimensions

D-PAK









(ROTATED -90°) SCALE: 12X

- NOTES: UNLESS OTHERWISE SPECIFIED

 A) THIS PACKAGE CONFORMS TO JEDEC, TO-252, ISSUE C, VARIATION AA.

 B) ALL DIMENSIONS ARE IN MILLIMETERS.
 C) DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994.

 D) HEAT SINK TOP EDGE COULD BE IN CHAMFERED CORNERS OR EDGE PROTRUSION.
 E) PRESENCE OF TRIMMED CENTER LEAD IS OPTIONAL.

 - IS OPTIONAL.
 - F) DIMENSIONS ARE EXCLUSSIVE OF BURSS, MOLD FLASH AND TIE BAR EXTRUSIONS.
 - LAND PATTERN RECOMENDATION IS BASED ON IPC7351A STD T0220P1003X238-3N.

 - DRAWING NUMBER AND REVISION: MKT-T0252A03REV8

Dimensions in Millimeters





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